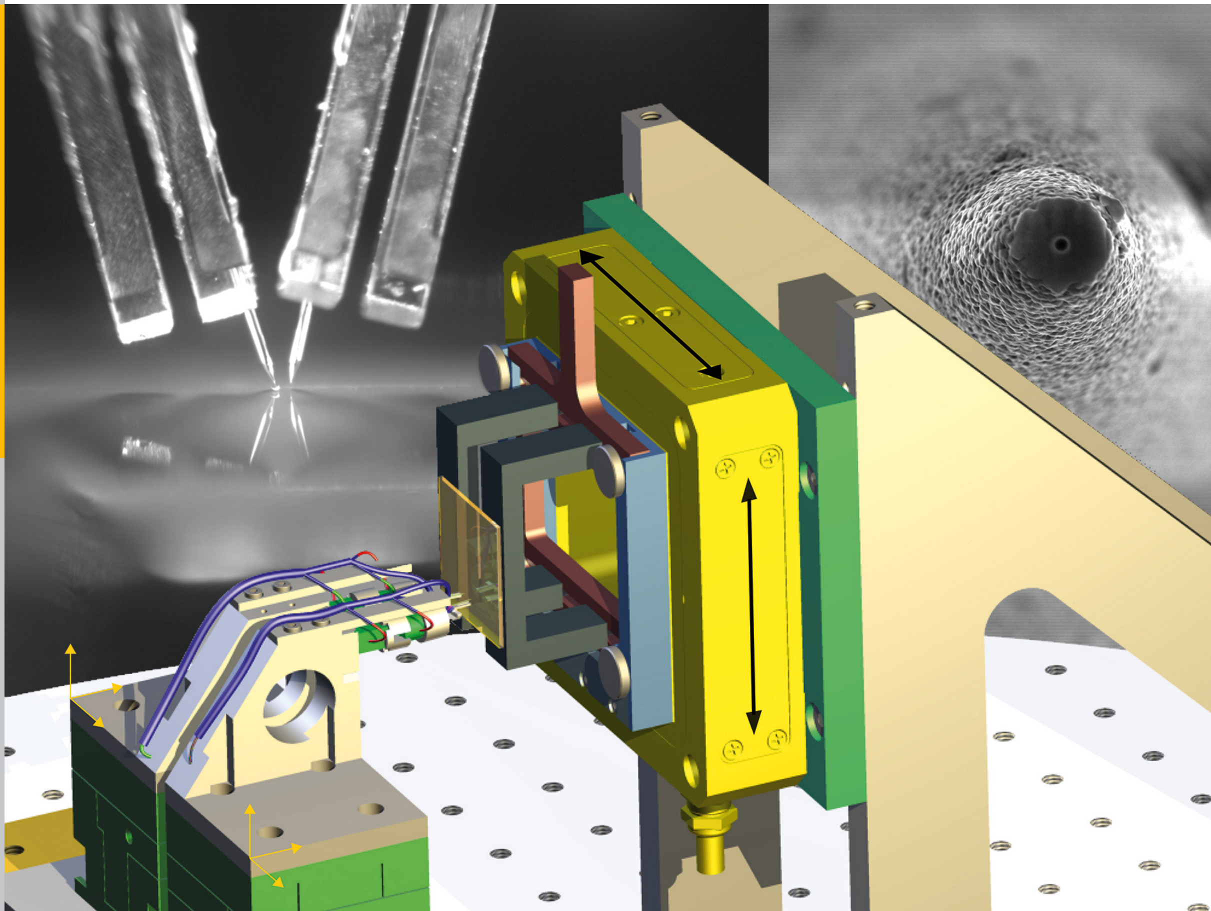
Investigation of light propagation in thin-film silicon solar cells by dual-probe scanning near-field optical microscopy

Stephan Lehnen



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